

# Condura<sup>®</sup>.classic Metal Ceramic Substrates Condura.extra DPS<sup>(1)</sup>

## **Alumina DCB facts**

- Alumina ceramic Al<sub>2</sub>O<sub>3</sub> (96 %) Thicknesses<sup>(2)</sup>: 0.25 mm/Condura.extra0.32 mm/ 0.38mm/0.63 mm
- Direct Copper Bonding Cu-OFE Thicknesses<sup>(2)</sup>: 0.2 mm/0.25 mm/0.3 mm/0.4 mm
- Single unit or master card size 7 " x 5 " (usable area)
- Surface finish: bare Cu, Ni, Ni/Au (others planned)

# **Key features**

- Pre-qualified solutions & optimized surfaces
- Fast sample delivery target for standard material combinations

Europe: 5 working days

Worldwide: 15 working days (after drawing approval)

■ Improved warpage / customization possible

Main properties raw Al <sub>2</sub> O <sub>3</sub>		
	Rating	Unit
Thermal conductivity @ 20 °C	≥ 20	W/m.K
Bending strength	> 450	N/mm2
Young's modulus	≥ 300	GPa
Coefficient of thermal expansion (Al <sub>2</sub> 0 <sub>3</sub> ) @ 100 °C - 600 °C	6.7 - 8.7	ppm/k

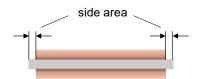
<sup>\*</sup>Picture: substrate layout by courtesy of Fraunhofer IISB (1) Development Product Information Sheet, preliminary values

<sup>(2)</sup> Different material combinations on request

# Condura<sup>®</sup>.classic Design Rules Al<sub>2</sub>O<sub>3</sub> DPIS<sup>(1)</sup>

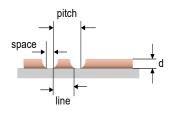
Material properties raw Al <sub>2</sub> O <sub>3</sub> <sup>(3)</sup>		
	Rating	Unit
Density	> 3.73	g/cm3
Electrical resistivity	≥ 1013	Ohm.cm
Dielectric strength	> 15	kV/mm

# Copper free area



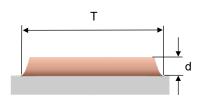
Thickness Cu [mm]	Min. side area [mm]
0.20	0.20
0.25	0.23
0.30	0.25
0.40	0.35

# Structuring



Thickness Cu [mm]	Min. space [mm]	Min. line [mm]	Min. pitch [mm]
0.20	0.40	0.40	0.80
0.25	0.45	0.45	0.90
0.30	0.50	0.50	1.00
0.40	0.60	0.60	1.20

# Etching tolerance

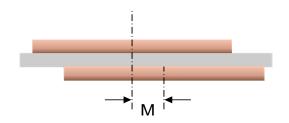


Tolerance length & width [mm]	Thickness Cu [mm]
Ttyp. = $\pm 0.15$	d = 0.2
Ttyp. = $\pm 0.20$	d ≤ 0.3
Ttyp. = $\pm 0.20$	d ≤ 0.4

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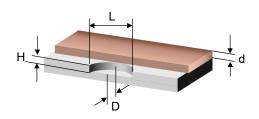
# Tolerance and chip off

## Tolerance



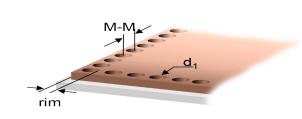
 $\label{eq:mismatch M} \mbox{Mismatch M} \leq 0.1 \mbox{ mm}$   $\mbox{Tolerance of total thickness} = + 7 \mbox{ \% / -10 \%}$ 

# Chip-off at ceramic edge



Length L  $\leq$  d Depth D  $\leq$   $\frac{1}{2}$ d Height H  $\leq$   $\frac{1}{2}$ d

# Dimple structure



Thickness Cu [mm]	Dimple area rim [mm]	Dimple diamter d <sub>1</sub> [mm]	Dimple pitch M-M [mm]
0.20			
0.25		To be agreed	
0.30			
0.40			

#### **Dimensions**

General dimensions	Rating (mm)
Master card	138 x 190.5
Max. usable area	127 x 178
Minimum dimension for ceramic thickness ≤ 0.63 mm	10 x 10 (smaller on request)

Tolerances of single parts	Rating (mm)
Ceramic thickness ≤ 0.63 mm	+ 200 μm - 50 μm

Warpage behavior depends on specific layout, single part size and material combination and can only be specified after initial sample preparation.

Surface plating	
Plating Method	Thickness (um)
Electroless Ni	3 - 7 (9% ± 2 % P)
Electroless NiAu	Ni 3 - 7 (9 % ± 2 % P) Au Class 1: 0.01 - 0.05 Au Class 2: 0.03 - 0.13

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## Metal & hole properties

## Roughness

Rmax =  $50 \mu m$ 

 $Ra \le 3.5 \mu m$  $Ra \le 1 \mu m$ 

 $Rz \le 24 \mu m$  $Rz \le 16 \mu m$ 

> Different roughness by request

## Minimum hole diameter

 $d_{hole} = 1 \text{ mm}$ 

Electrical conductivity raw copper

 $G_{CII} = 58 \cdot 10^6 \text{ S/m}$ 

Thickness Cu Copper peeling strength

0.30mm > 4 N/mm

## **HET Academy R&D Application Center**

Bonding Wires and Metal Ceramic

## Application conditions and assembly optimization

#### Thermal shock test cycles

-55 °C up to +150 °C

**Under Investigation** 

#### Customized surface for assembly process

Optimization of surface and assembly process parameters available or in developement cooperation for:

- Sintering
- Solder wetting
- Heavy wire bondability

## Heraeus Electronics offers:

- Reliable IATF 16949 certified supply of:
- Condura® + for example
- To be your competent one-stop materials solutions partner!
- $\sqrt{\text{Condura}^{\text{(B)}}}$ .prime AMB-Si<sub>3</sub>N<sub>4</sub> (active metal brazed Si<sub>3</sub>N<sub>4</sub>)
- √ Condura®.extra DCB-ZTA (zirconia-toughened alumina)
- √ Condura®.classic DCB-Al2O3 (direct copper bonded Al<sub>2</sub>O<sub>3</sub>)
- √ Engineering Services (Simulation, Prototype Design & Assembly) Testing an Qualification, Material Analysis)
- √ Pre-applied sinter / solder

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